## Notic of References Cited Application/Control No. 10/670,040 Examiner Sean E. Vincent Applicant(s)/Patent Under Re xamination KIM ET AL Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-3,387,940 A	06-1968	MCHENRY EDGAR R; et. al.	423/448
	В	US-4,122,139 A	10-1978	Yajima et al.	264/44
	С	US-5,358,910 A	10-1994	Atwell et al.	501/88
	D	US-5,571,848 A	11-1996	Mortensen et al.	521/61
	ш	US-5,750,449 A	05-1998	Niihara et al.	501/80
	F	US-6,087,024 A	07-2000	Whinnery et al.	428/613
	G	US-6,231,793 B1	05-2001	Strasser et al.	264/45.1
	Η	US-5,558,908	09-1996	Lukacs III et al.	427/228
	_	US-5,616,650	04-1997	Becker et al.	525/102
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	ø					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	υ					
	V					
	w	·				
	×					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.